September 17, 2015 FIT 2015





# 統計的パターンマイニング

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#### **Outline**

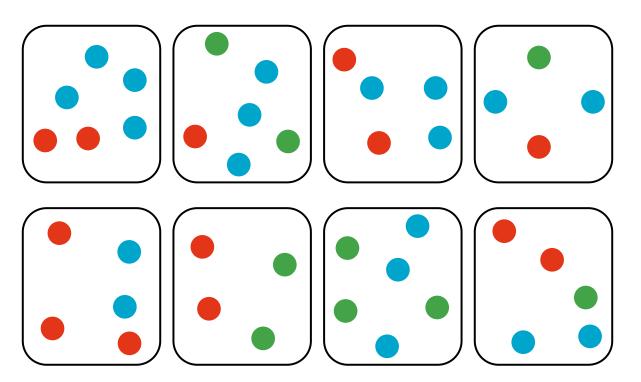
- (Discriminative) Pattern mining
- Statistical hypothesis testing of patterns
- Multiple hypothesis testing in pattern mining
- Testable patterns
- Permutation testing in pattern mining
- Conclusion

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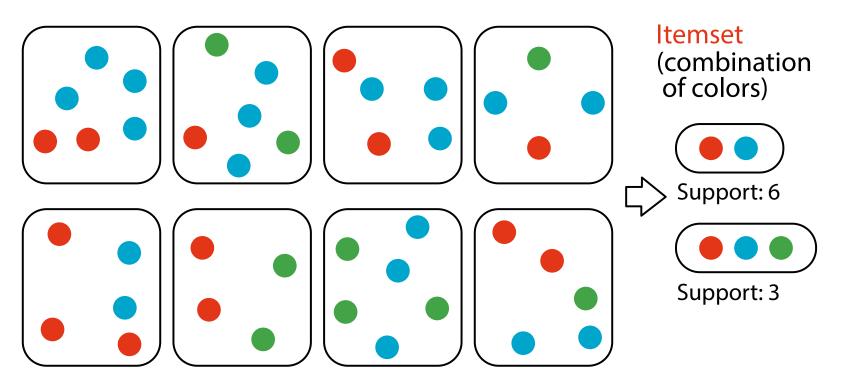
#### **Itemset Mining**

Find interesting combinatorial patterns from massive data



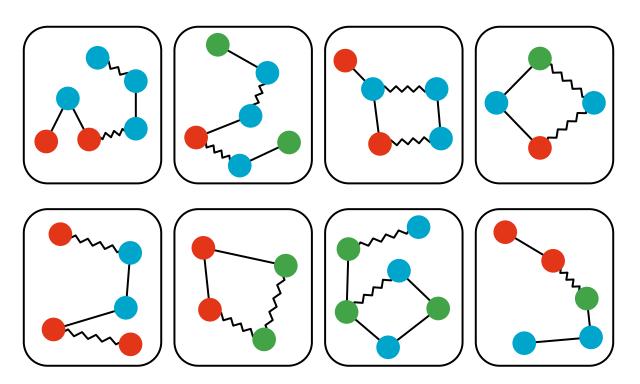
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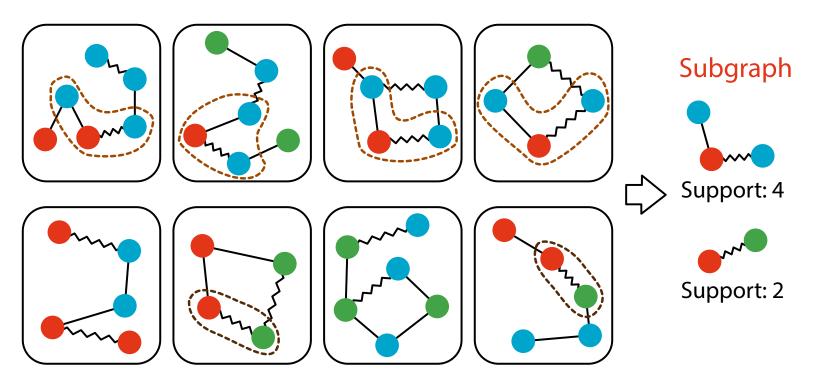
# **Subgraph Mining**

Find interesting combinatorial patterns from massive data



## **Subgraph Mining**

Find interesting combinatorial patterns from massive data



#### **Apriori on Itemset Lattice**

# Transaction database

- ID 1: •
- ID 2: •
- ID 3: •
- ID 4: • •
- ID 5: •
- ID 6:
- ID 7: •
- ID 8: • •

#### **Apriori on Itemset Lattice**

# Transaction database



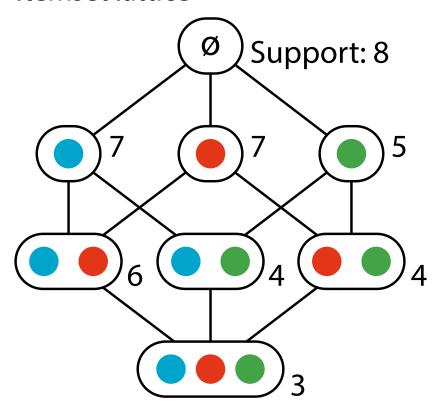








#### Itemset lattice



#### Apriori principle:

Support is monotonically decreasing

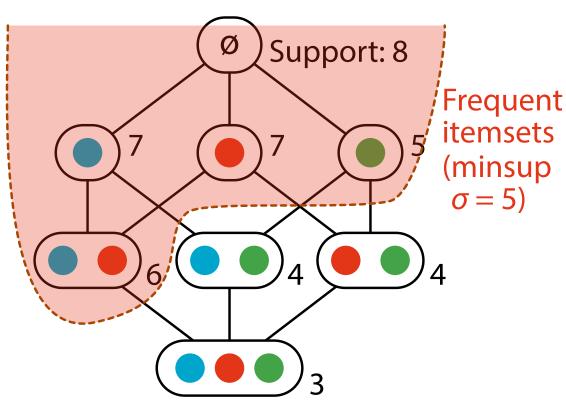
#### **Apriori on Itemset Lattice**

# Transaction database





#### **Itemset lattice**



#### Apriori principle:

Support is monotonically decreasing

#### Discriminative Itemset Mining

**Database** 

- Find discriminative patterns from supervised data
  - e.g. Genome-wide association studies in Bioinformatics

**Positive** Negative

#### Discriminative Itemset Mining

**Database** 

- Find discriminative patterns from supervised data
  - e.g. Genome-wide association studies in Bioinformatics

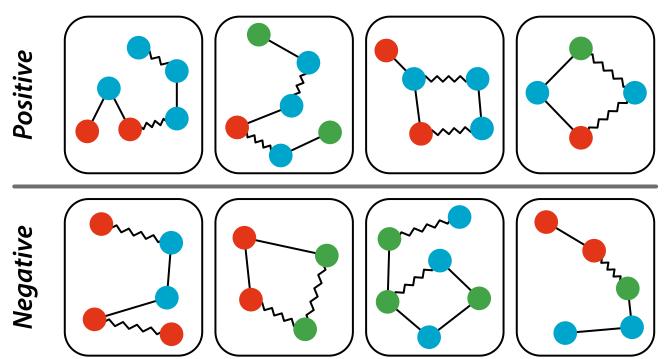
Discriminative Itemset

Support: (4, 2)

Support: (3, 1)

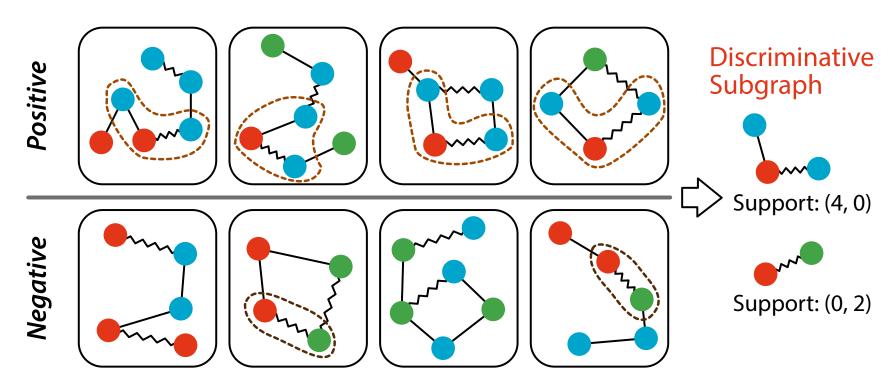
#### **Discriminative Subgraph Mining**

- Find discriminative patterns from supervised data
  - e.g. Drug discovery



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#### Agenda

- In discriminative pattern mining:
- 1. How to measure the discriminability of patterns?
- 2. How to enumerate all discriminative patterns?

#### Agenda

- In discriminative pattern mining:
- 1. How to measure the discriminability of patterns?
- 2. How to enumerate all discriminative patterns?
  - Answer to 1:
    - Compute the p-value via statistical hypothesis testing
    - Discriminative pattern ←⇒ (Statistically) Significant pattern
  - Answer to 2:
    - Integrate evaluation of discriminability and enumeration of patterns

#### **Outline**

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### Computing p-value of Pattern

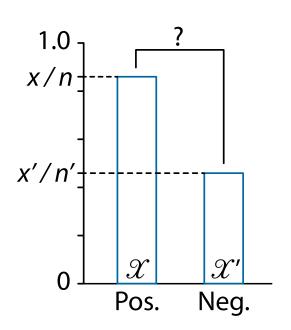
• Given positive and negative sets of transactions  $\mathcal{X}$ ,  $\mathcal{X}'$ 

$$-|\mathcal{X}|=n, |\mathcal{X}'|=n' (n \leq n')$$

 The p-value of each pattern H is determined by the Fisher's exact test

$$- x = |\{X \in \mathcal{X} \mid H \subseteq X\}|$$

	Occ.	Non-occ.	Total			
$\mathscr{X}$ (Pos.	) X	n – x	n			
$\mathcal{X}'$ (Neg	.) X'	n'-x'	n'			
Total	$X + X'$ $= \sigma$	(n-x) + $(n'-x')$	n + n'			
Support						



#### Fisher's Exact Test

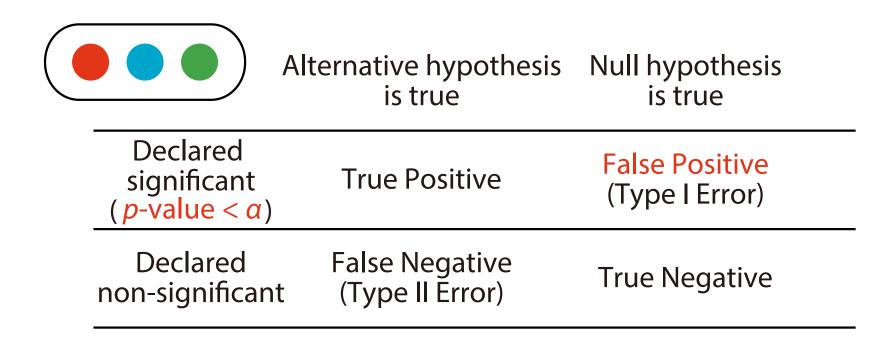
• The probability q(x) of obtaining x and x' is given by the hypergeometric distribution:

$$q(x) = \binom{n}{x} \binom{n'}{x'} / \binom{n+n'}{x+x'}$$

Occ. N	lon-occ.	Total	q(X)			
$\mathcal{X}$ (Pos.) $X$	n – x	n	oility			
$\mathcal{X}'$ (Neg.) $x'$	n'-x'	n'	Probability	<i>p</i> -value		
Total $x + x' = \sigma + \sigma$	(n-x)	n + n'	Pro		-	
Su	ıpport	 = max	-0 + x{0 <i>. x</i>	X <sub>min</sub> - x' - n'}	X	$= \min\{x + x', n\}$
				,		11/40

0.3

### **Hypothesis Test for Each Pattern**



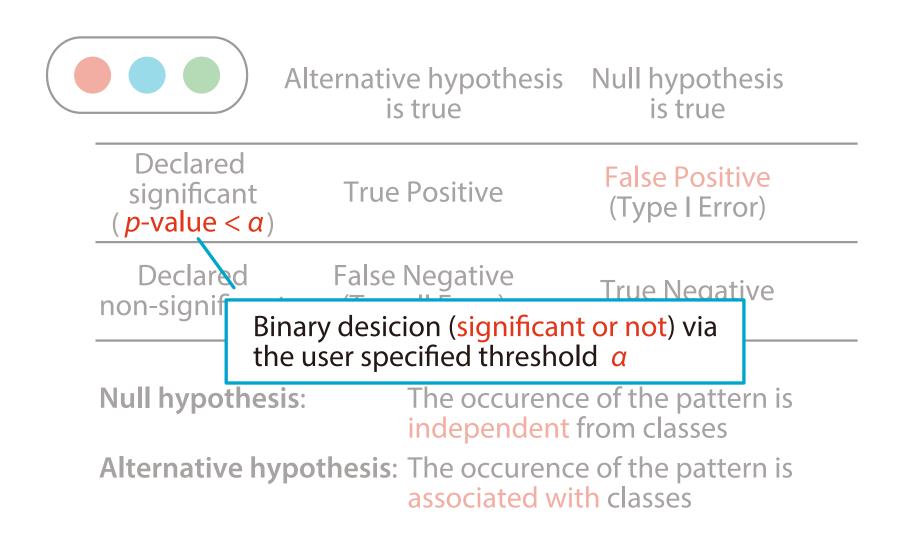
**Null hypothesis:** The occurrence of the pattern is

independent from classes

**Alternative hypothesis**: The occurrence of the pattern is

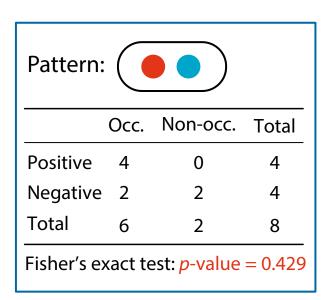
associated with classes

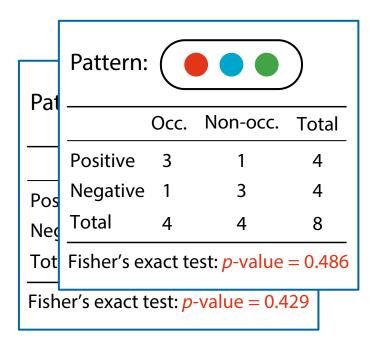
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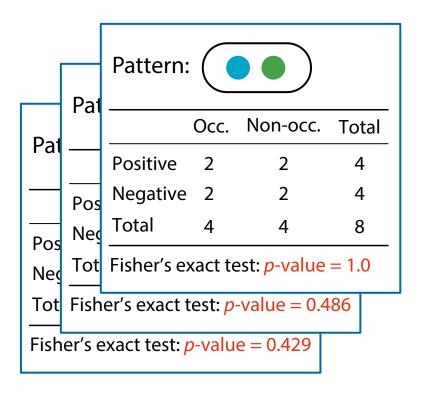


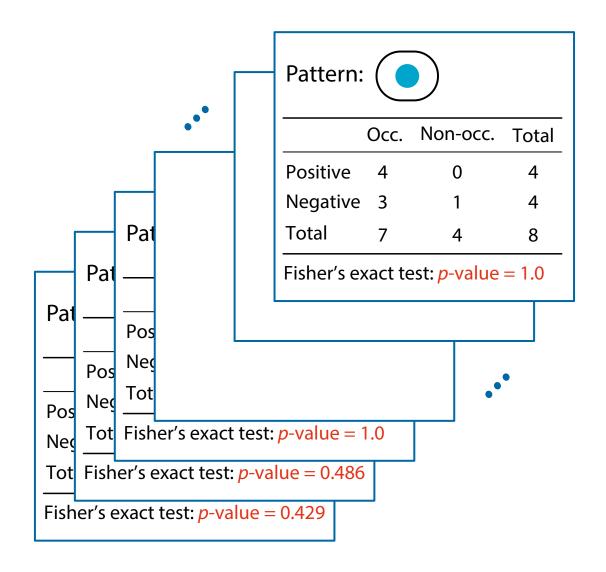
#### **Outline**

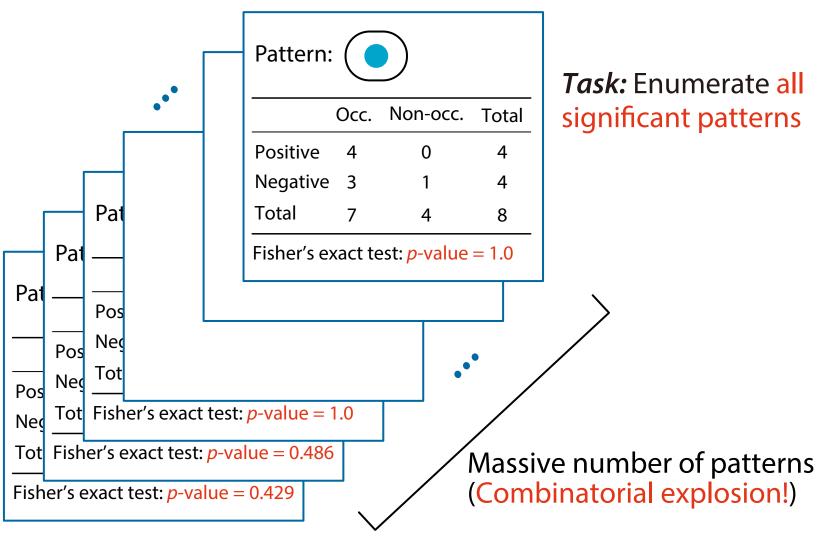
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#### **Multiple Testing Correction**

- In each test, [probability of having a false positive]  $\leq \alpha$
- If we repeat *m* tests, *αm* patterns can be false positives
  - Too many if m is large!
- Example in itemset mining:
  - For 100000 items, #patterns = 2<sup>100000</sup>
  - Set significance level  $\alpha = 0.01$
  - Number of false positives:  $0.01 \cdot 2^{100000} = 10^{30101}$

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  - Set significance level  $\alpha = 0.01$
  - Number of false positives:  $0.01 \cdot 2^{100000} = 10^{30101}$
- FWER (family-wise error rate): Probability of having more than one false positives among all patterns
  - One of the standard criteria in multiple testing
  - FWER =  $1 (1 \alpha)^m$  if patterns are independent

### **Controlling the FWER**

- FWER = Pr(FP > o)
  - FP: Number of false positives
- To achieve FWER =  $\alpha$ , change the significance level for each pattern from  $\alpha$  to  $\delta$ 
  - $\delta$ : corrected significance level
  - $-\delta \leq \alpha$

## **Controlling the FWER**

- FWER = Pr(FP > 0)
  - FP: Number of false positives
- To achieve FWER =  $\alpha$ , change the significance level for each pattern from  $\alpha$  to  $\delta$ 
  - $\delta$ : corrected significance level
  - $-\delta \leq a$
- Objective is to optimize (maximize)  $\delta$ :

```
\delta^* = \underset{\delta}{\operatorname{argmax}} \operatorname{FWER}(\delta) \quad \text{s.t.} \operatorname{FWER}(\delta) \leq \alpha
```

- FWER( $\delta$ ): FWER at corrected significance level  $\delta$ 
  - Cannot be evaluated in closed form (simple but not easy!)
- Bonferroni correction is popular:  $\delta_{Bon}^* = \alpha/m$

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### Minimum Achievable p-value $\Psi(\sigma)$

• Consider the minimum achievable p-value  $\Psi(\sigma)$  of a pattern H for its support  $\sigma = |\{X \in \mathcal{X} \cup \mathcal{X}' \mid H \subseteq X\}|$ 

$$- \Psi(\sigma) = \min\{p(x) \mid x_{\min} \le x \le x_{\max}\}\$$

$$\circ x_{\min} = \max\{o, \sigma - n'\}, x_{\max} = \min\{\sigma, n\}$$

			0.5				
Occ. N	on-occ.	Total	' q(X)				Minimum
$\mathscr{X}$ (Pos.) $x$	n – x	n	oility				achievable <i>p</i> -value
$\mathcal{X}'$ (Neg.) $x'$	n'-x'	n'	Probability				
Total $x + x'$ $(r = \sigma)$ +	(n-x)	n + n'	Prc				
Su	ipport	= m	-0 ax{0, <i>f</i> (ر	<i>X</i> <sub>min</sub> H) − <i>n</i> ′}	X	=	$= \min\{f(H), n\}$
			- / (	•			18/40

 $0.3^{-1}$ 

## Computing $\Psi(\sigma)$

• Consider the minimum achievable p-value  $\Psi(\sigma)$  of a pattern H for its support  $\sigma = |\{X \in \mathcal{X} \cup \mathcal{X}' \mid H \subseteq X\}|$ 

$$\Psi(\sigma) = \binom{n}{\sigma} / \binom{n+n'}{\sigma}$$

		_					
	Occ.	Non-occ.	Total	/ q(X)			Minimum
$\mathscr X$ (Pos.)	σ	n – σ	n	oility			achievable <i>p</i> -value
$\mathscr{X}'$ (Neg.)	0	n′	n'	Probability			
Total	σ	(n – σ) + n′	n + n'	Prc			
Most bi	iased	case $(\sigma < n)$	= m	ax{0, <i>f</i> (	X <sub>min</sub> H) – n'}	X	$= \min\{f(H), n\}$
							19/40

0.3

#### **Testability**

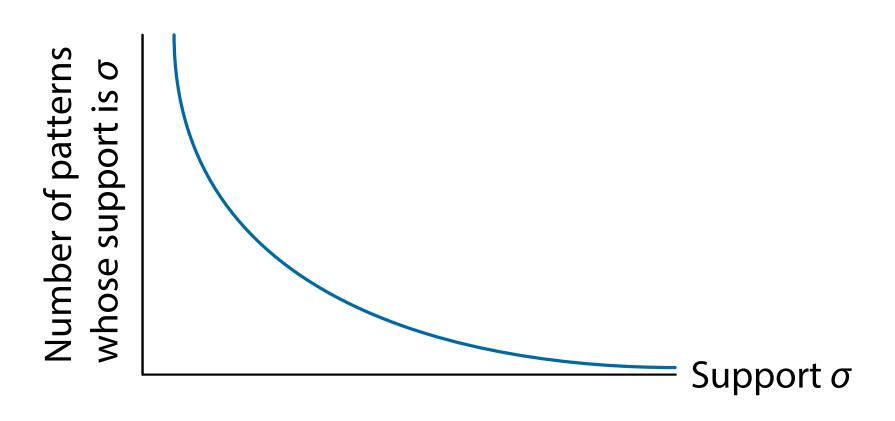
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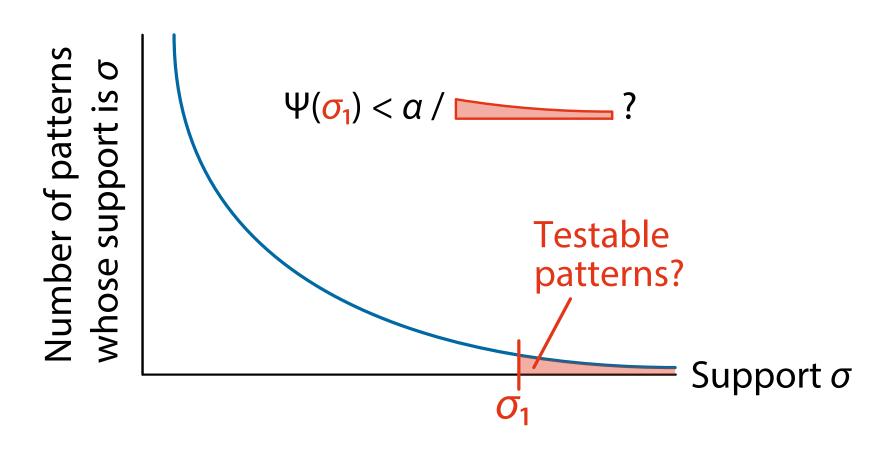
$$\Psi(\sigma) = \binom{n}{\sigma} / \binom{n+n'}{\sigma}$$

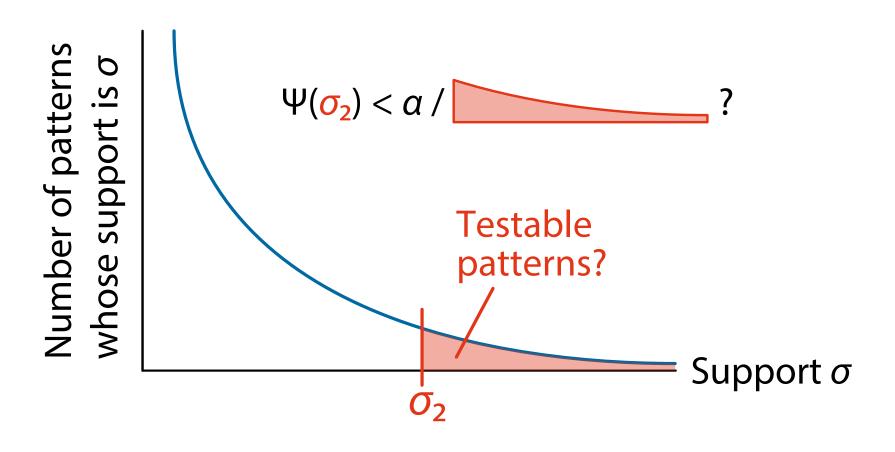
Tarone (1990) pointed out (and Terada et al. (2013) revisited):

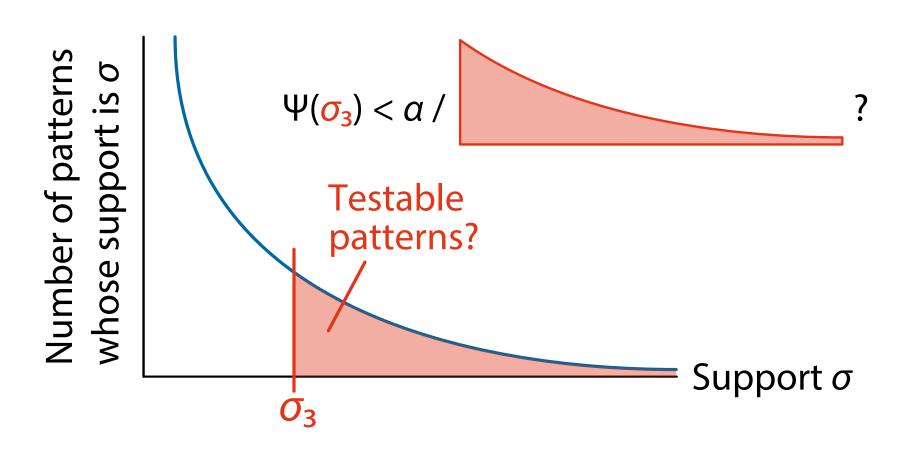
For a pattern H, if  $\Psi(\sigma)$  is larger than the significance threshold, this is untestable and we can ignore it

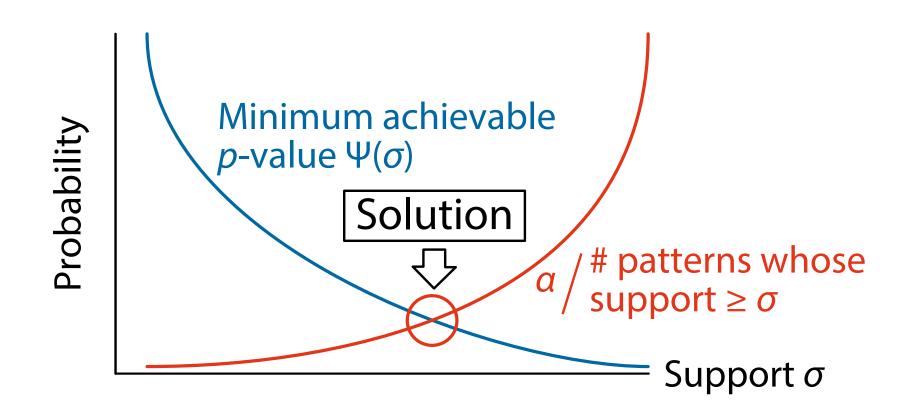
### **Finding Testable Patterns**



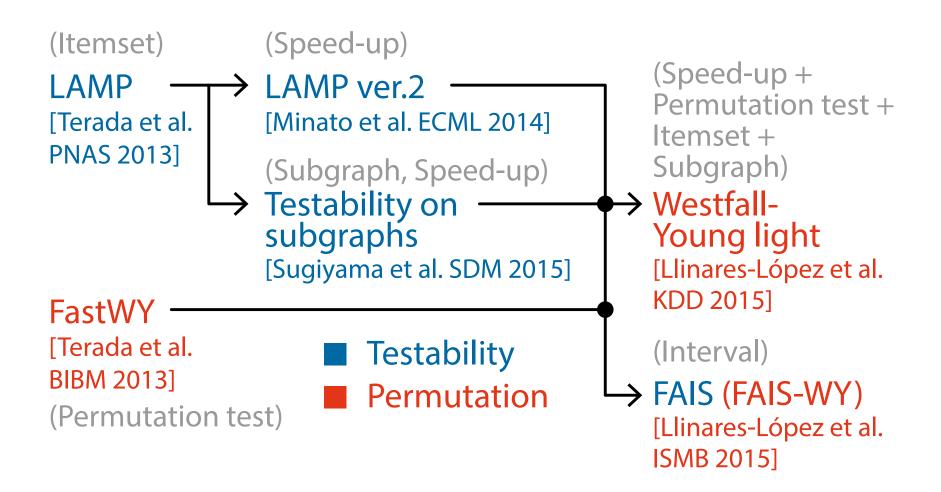




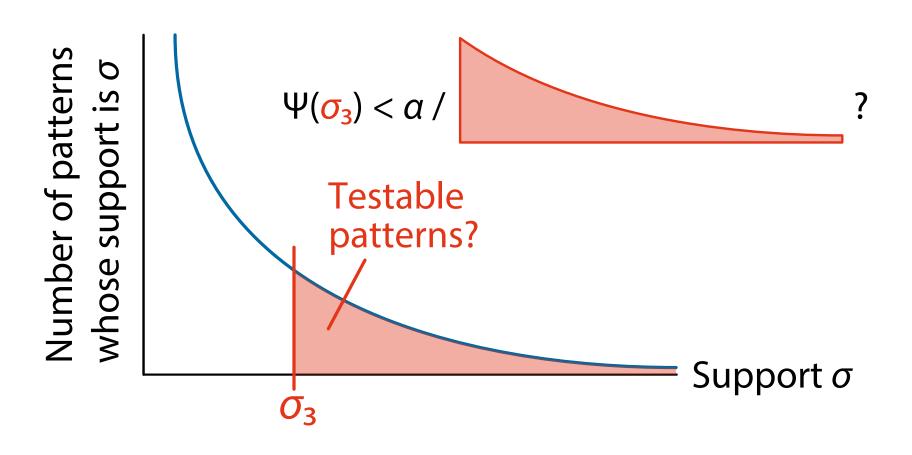




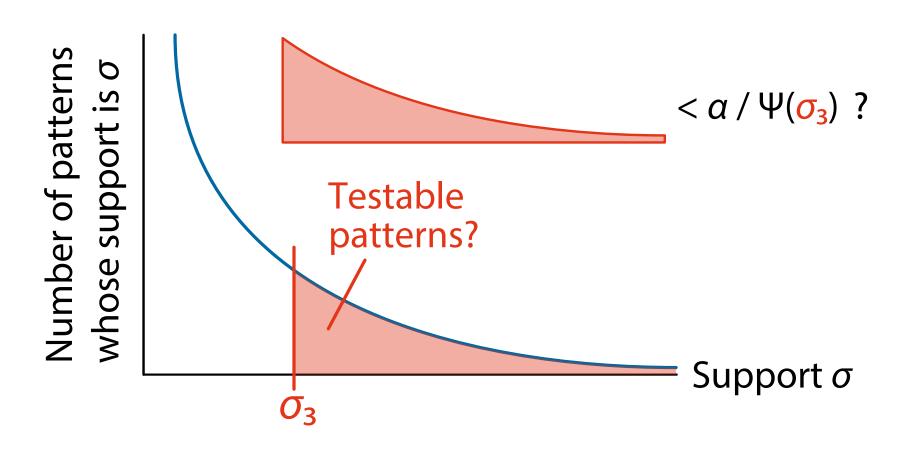
## State-of-the-art



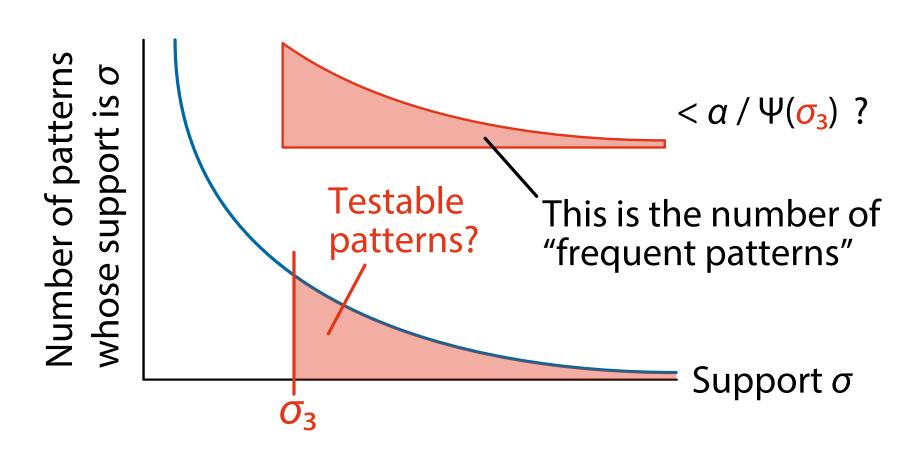
## **How to Find Testable Patterns?**

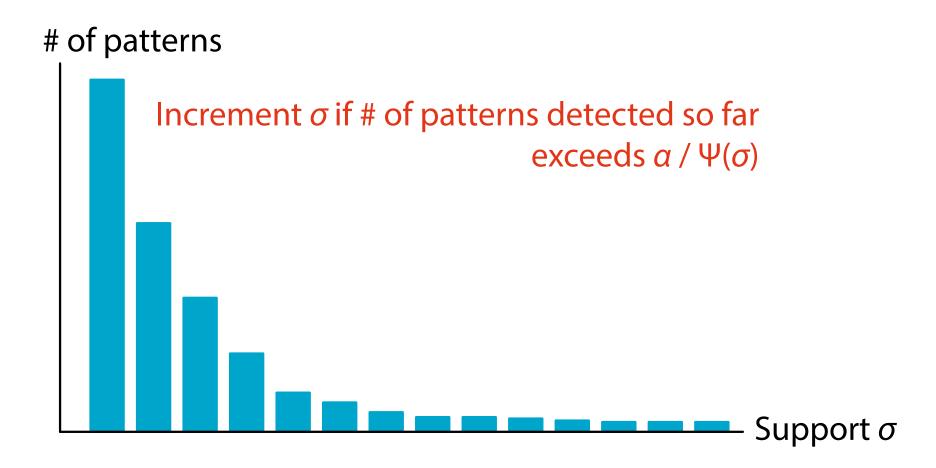


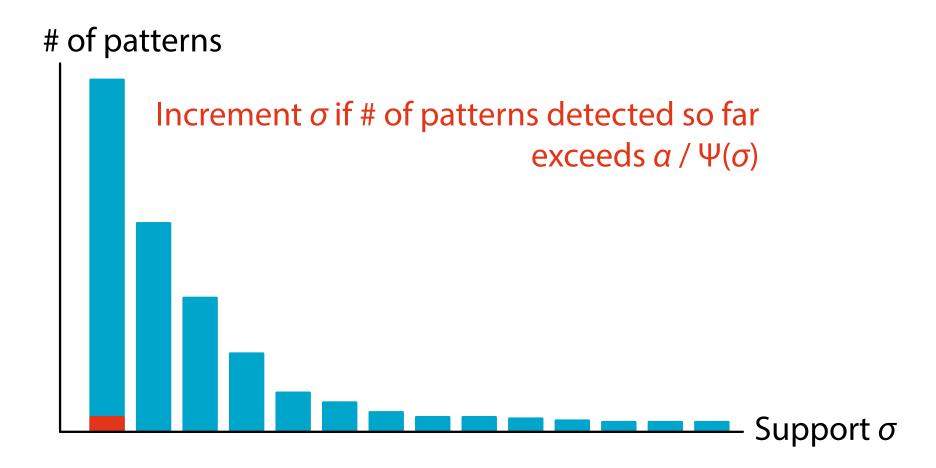
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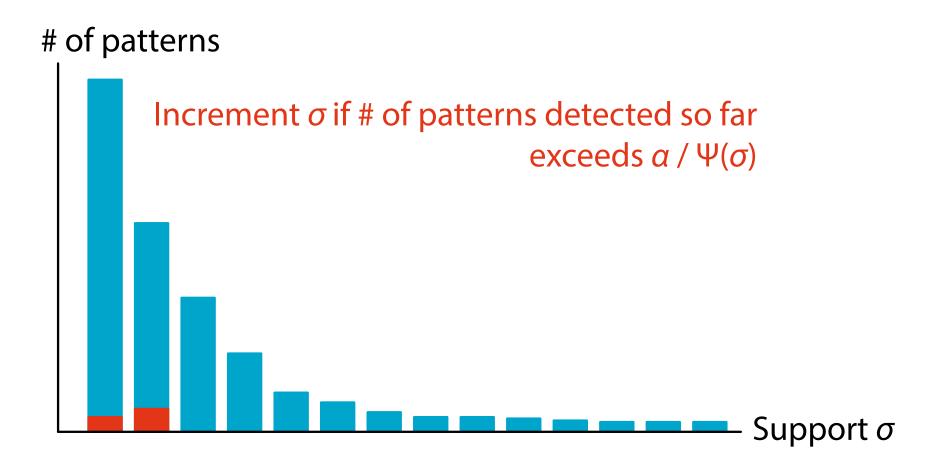


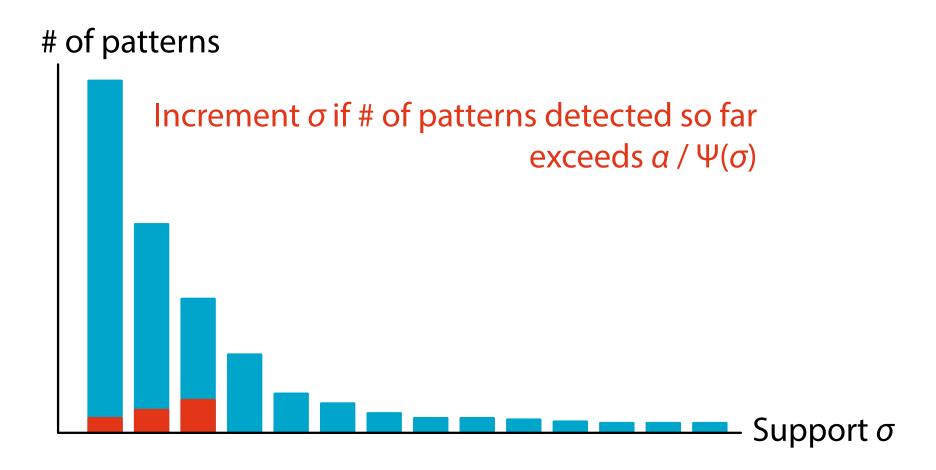
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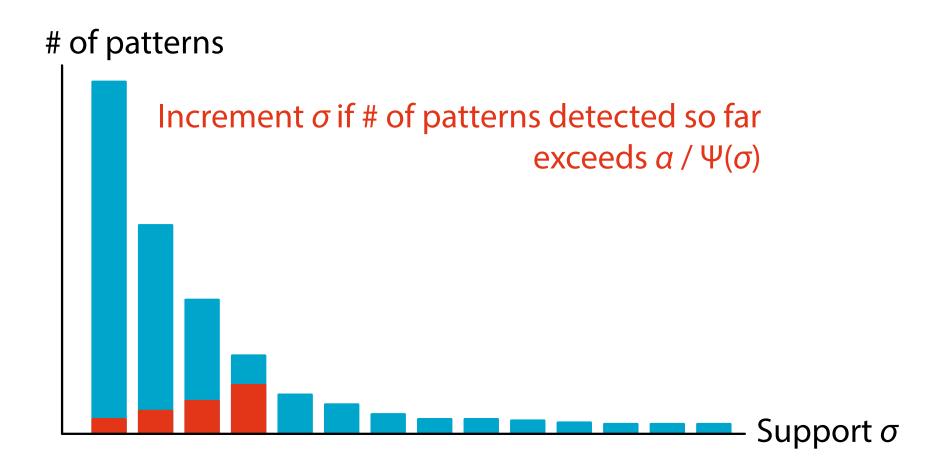


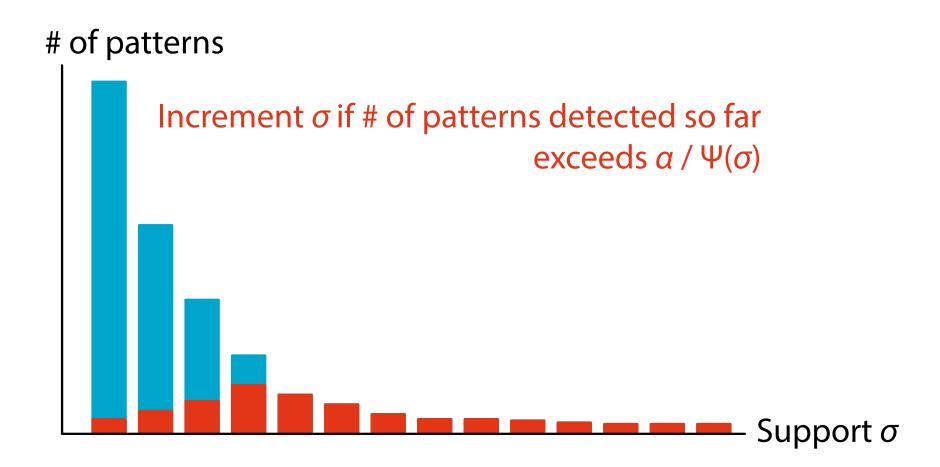


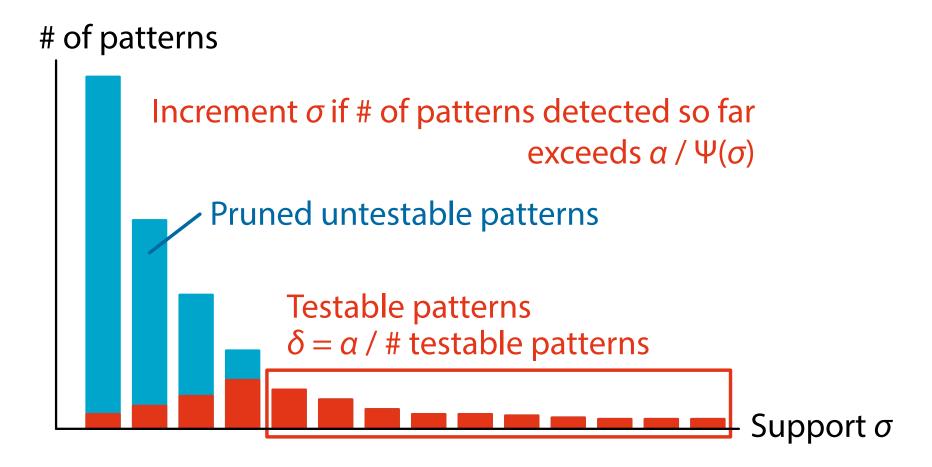




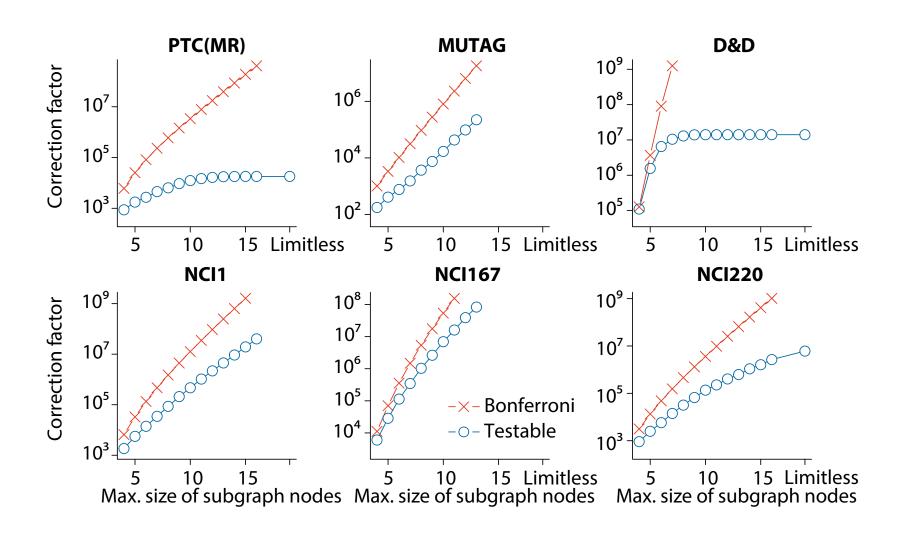








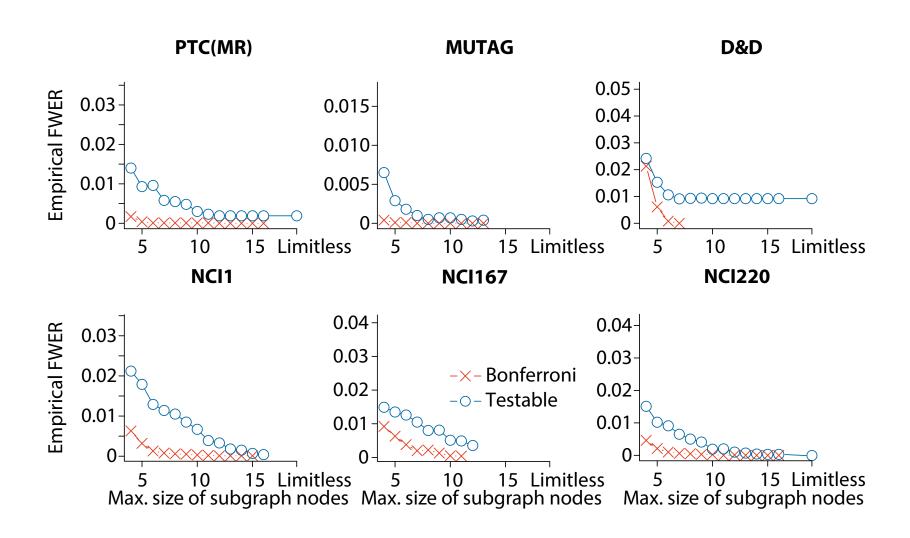
## # Testable Patterns in Subgraph Mining



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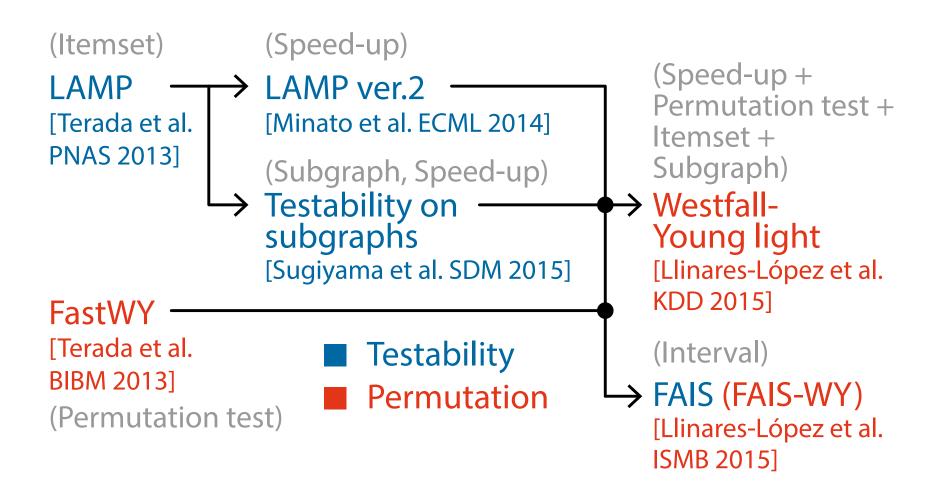
## **FWER Is Still Too Low!**



## **Take Dependencies into Account**

- Problem: Dependencies between patterns are not considered
- Solution: Permutation test
  - Repeat random permutation of class labels (10<sup>3</sup> ~ 10<sup>4</sup> times)
  - Get the null distribution of p-values
  - The optimal correction factor can be obtained

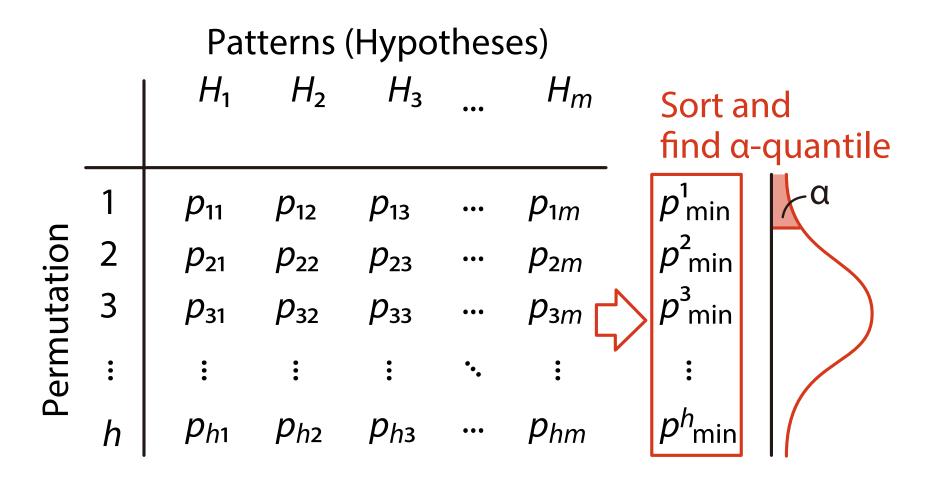
## State-of-the-art



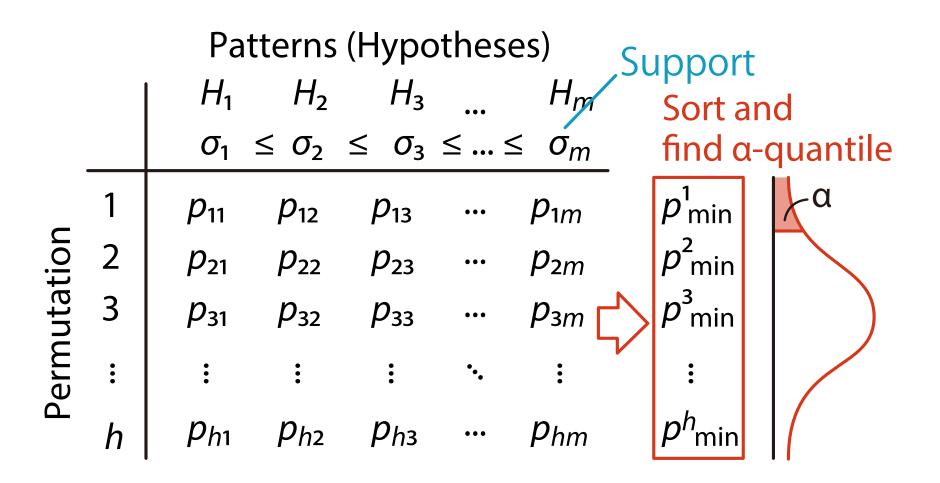
# **Westfall-Young Permutation**

- 1. Randomly permute class labels
- 2. Compute *p*-values for all patterns using the permuted class labels
- 3. Find the minimum p-value  $p_{min}$  among them
  - FP > o  $\iff$   $p_{\min} < \delta$ 
    - FP: Number of false positives
- 4. Repeat steps 1 to 3 h times and obtain  $p_{\min}^1, p_{\min}^2, \dots, p_{\min}^h$ 
  - FWER( $\delta$ )  $\approx |\{i : p_{\min}^i \leq \delta\}| / h$
- 5.  $\delta^*$  is the  $\alpha$ -quantile of  $p_{\min}^1, p_{\min}^2, \dots, p_{\min}^h$

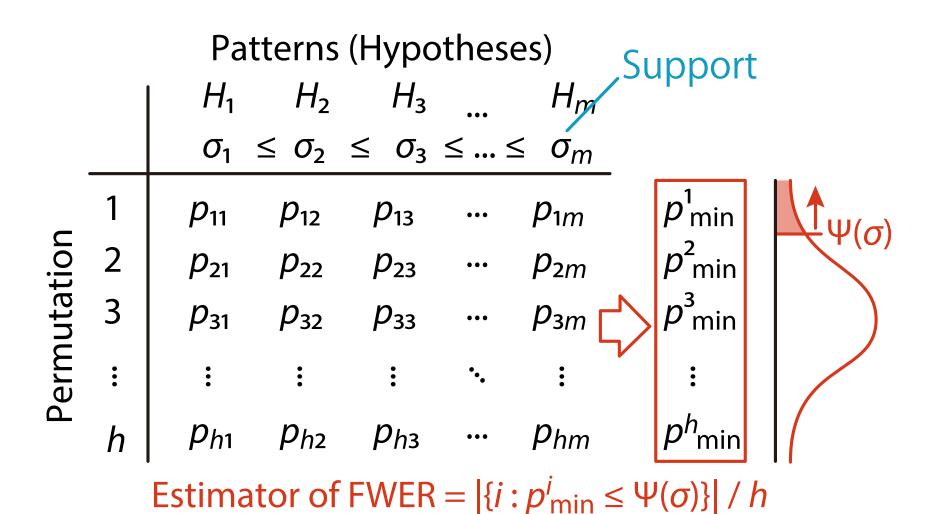
# **Westfall-Young Permutation**



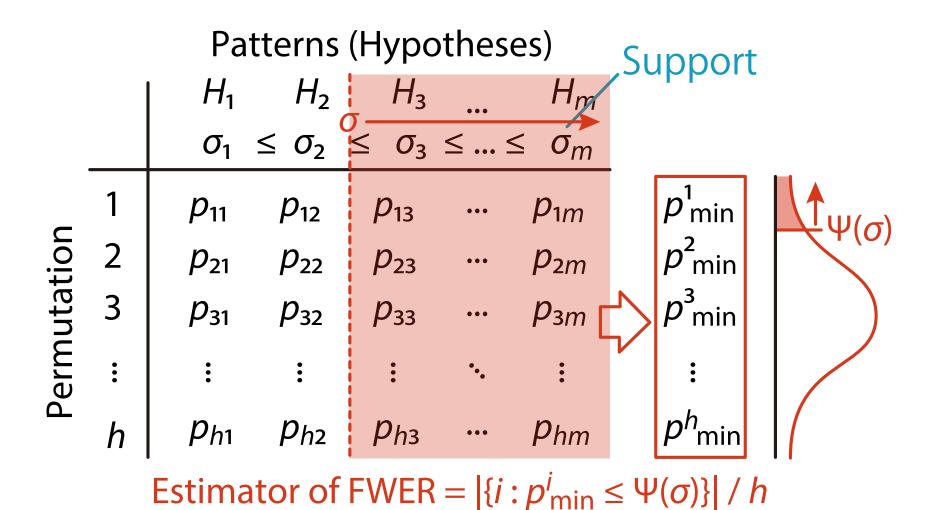
# **Using Support for Estimating FWER**



# **Estimating FWER**



# **Estimating FWER**

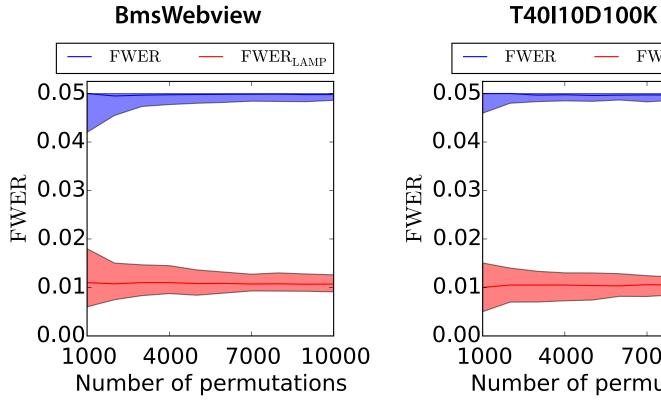


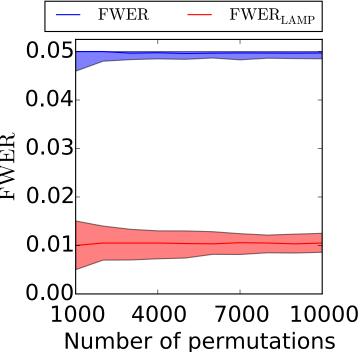
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# "Westfall-Young light"

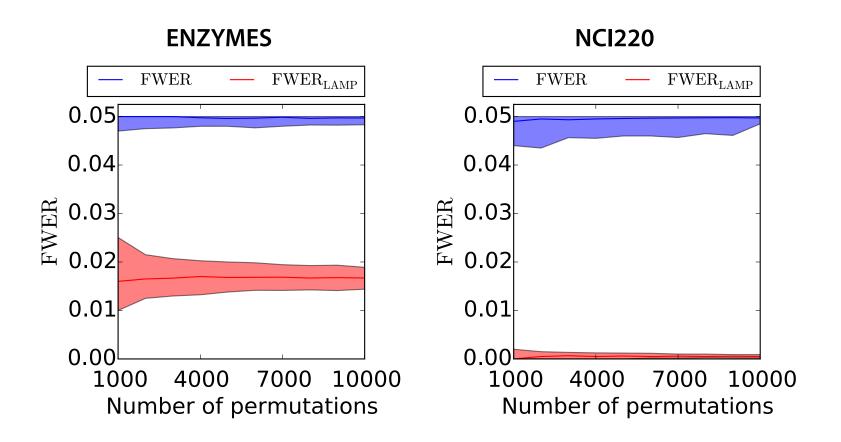
- Precompute h permuted labels;  $\sigma \leftarrow 1$ ;  $p_{\min}^{i} \leftarrow 1$
- Westfall-Young light does the following whenever a miner (like LCM) finds a new frequent pattern H:
  - for i ← 1 to h do:
    - $\circ p^i \leftarrow \text{the } p\text{-value of } H \text{ for } i\text{th permutation}$
    - $\circ p_{\min}^i \leftarrow \min\{p_{\min}^i, p^i\}$
  - FWER ←  $|\{i : p_{\min}^i \le \Psi(\sigma)\}| / h$ // Ψ(σ) is the min. achievable p-value at σ
  - while FWER >  $\alpha$  do:
    - $\circ \sigma \leftarrow \sigma + 1$  //  $\sigma$  is the minimum support
    - ∘ FWER  $\leftarrow |\{i: p_{\min}^i \le \Psi(\sigma)\}| / h$
  - Go children of H

# **FWER in Itemset Mining**





# **FWER in Subgraph Mining**



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#### Conclusion

- The area of significant pattern mining is emerging
  - Find statistically significant combinatorial patterns while controlling false positive rate
- Pattern mining, a classical yet central topic in data mining, can be enriched by introducing statistical assessment
  - Can be applied in scientific fields such as biology

# **Appendix**

## Papers about Testability

- Tarone, R.E.:
   A modified Bonferroni method for discrete data Biometrics (1990)
- [LAMP] Terada, A., Okada-Hatakeyama, M., Tsuda, K., Sese, J.: Statistical significance of combinatorial regulations, *Proc. Natl. Acad. Sci. USA* (2013).
- [LAMP ver.2] Minato, S., Uno, T., Tsuda, K., Terada, A., Sese, J.: Fast Statistical Assessment for Combinatorial Hypotheses Based on Frequent Itemset Mining ECML PKDD 2014
- Sugiyama, M., Llinares, F., Kasenburg, N., Borgwardt, K.:
   Significant Subgraph Mining with Multiple Testing Correction, SIAM SDM 2015

# Papers about Permutation Testing

- Westfall, P. H. and Young, S. S.
   Resampling-based multiple testing: Examples and methods for p-value adjustment John Wiley & Sons (1993)
- [FastWY] Terada, A. and Tsuda, K. and Sese, J.:
   Fast Westfall-Young permutation procedure for combinatorial regulation discovery,
   IEEE BIBM 2013
- [Westfall-Young light] Llinares, F., Sugiyama, M., Papaxanthos, L., Borgwardt, K.:
   Fast and Memory-Efficient Significant Pattern Mining via Permutation Testing, ACM SIGKDD 2015

## Frequent Itemset Miners

- [Apriori] Agrawal, R. and Imieliński, T. and Swami, A.: Mining association rules between sets of items in large databases, ACM SIGMOD 1993
- [FP-Growth] Han, J. and Pei, J. and Yin, Y.: Mining frequent patterns without candidate generation, ACM SIGMOD 2000
- [LCM] Uno, T. and Asai, T. and Uchida, Y. and Arimura, H.:
   An efficient algorithm for enumerating closed patterns in transaction databases,
   DS 2004
   (won FIMI'04 competition)

# Frequent Subgraph Miners

- [AGM] Inokuchi, A. and Washio, T. and Motoda, H.: An Apriori-Based Algorithm for Mining Frequent Substructures from Graph Data, PKDD 2000
- [gSpan] Yan, X. and Han, J.: gSpan: Graph-based substructure pattern mining, ICDM 2002
- [GASTON] Nijssen, S. and Kok, J. N.:
   A Quickstart in Frequent Structure Mining Can Make a Difference, KDD 2004
- (comparison) Wörlein, M. and Meinl, T. and Fischer, I. and Philippsen, M.
  - A Quantitative Comparison of the Subgraph Miners MoFa, gSpan, FFSM, and Gaston, PKDD 2005
  - We used GASTON as it is the fastest